

**Search Notes**

Application/Control No.

10/760,505

Examiner

LOIS ZHENG

Applicant(s)/Patent under  
Reexamination

HIRAIWA ET AL.

Art Unit

1793

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
inventorship search	3/19/2008	LLZ
Updated EAST search	3/19/2008	LLZ